

Single Pulse Avalanche Energy

Thermal Resistance, Junction to Case

Thermal Resistance, Junction to Ambient

Operating and Storage Junction Temperature Range

Power Dissipation

Power Dissipation

Device Marking	Device	Package	Reel Size	Tape Width	Quantity	
FDMS5672	FDMS5672	Power 56	13"	12mm	3000 units	

T<sub>C</sub> = 25°C

T<sub>A</sub> = 25°C

**Thermal Characteristics** 

E<sub>AS</sub>

IP<sub>D</sub>

T<sub>J</sub>, T<sub>STG</sub>

 $R_{\theta JC}$ 

mJ

\٨/

°C

°C/W

337

78

2.5

-55 to +150

1.6

50

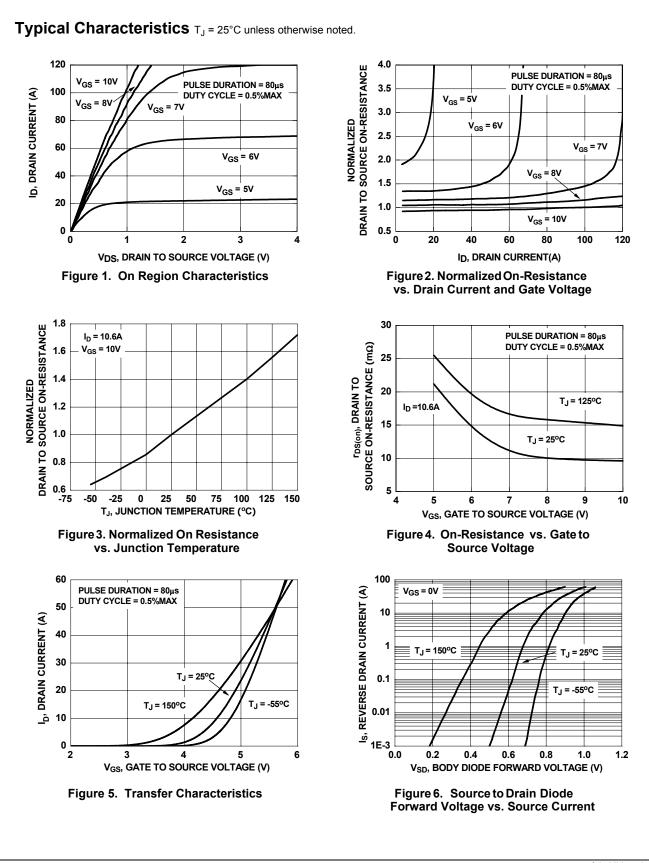
(Note 3)

(Note 1a)

(Note 1a)

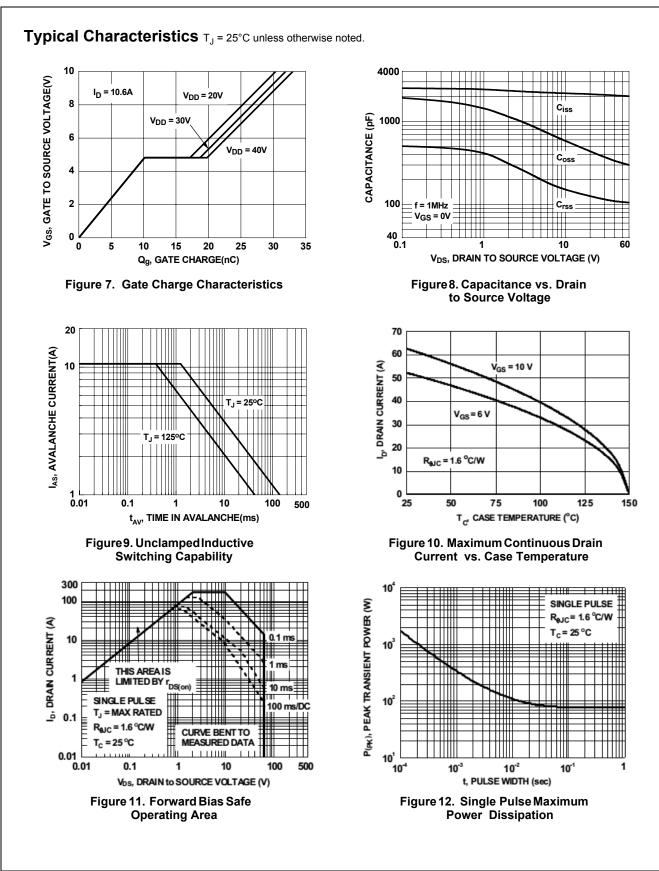
	Test Conditions	Min.	Тур.	Max.	Units
cteristics					
Drain to Source Breakdown Voltage	I <sub>D</sub> = 250μA, V <sub>GS</sub> = 0V	60			V
Breakdown Voltage Temperature Coefficient	$I_D = 250 \mu A$ , referenced to 25°C		59		mV/°C
Zero Gate Voltage Drain Current	V <sub>DS</sub> = 48V, V <sub>GS</sub> = 0V			1	μA
Gate to Source Leakage Current	$V_{GS}$ = ±20V, $V_{DS}$ = 0V			±100	nA
cteristics					
	$V_{CS} = V_{DS}$ . In = 250µA	2	3.2	4	V
		_	-		
Temperature Coefficient	$I_D = 250 \mu A$ , referenced to 25°C		-11		mV/°C
	V <sub>GS</sub> = 10V, I <sub>D</sub> = 10.6A		9.4	11.5	_
Drain to Source On Resistance	$V_{GS} = 6V, I_D = 8A$		13.0	16.5	mΩ
	$T_J = 125^{\circ}C$		15.0	18.0	
Forward Transconductance	V <sub>DS</sub> = 10V, I <sub>D</sub> = 10.6A		26		S
Characteristics					
			2100	2800	pF
	$V_{DS} = 30V, V_{GS} = 0V,$				pF
	f = 1MHz			180	pF
Gate Resistance	f = 1MHz		1.2		Ω
Characteristics					1
			16	29	ns
Rise Time	V <sub>DD</sub> = 30V, I <sub>D</sub> = 10.6A		17	31	ns
Turn-Off Delay Time	$V_{GS} = 10V, R_{GEN} = 6\Omega$		22	35	ns
Fall Time			8	16	ns
Total Gate Charge at 10V	$V_{GS} = 0V$ to 10V		32	45	nC
Gate to Source Gate Charge	$v_{DD} = 30V$		10		nC
Gate to Drain "Miller" Charge	ID - 10.0A		8.3		nC
rce Diode Characteristics					
	$V_{CC} = 0V_{LC} = 10.6A$ (Note 2)		0.80	1.20	V
-					ns
Reverse Recovery Charge	— I <sub>F</sub> = 10.6A, di/dt = 100A/μs		42	63	nC
	Coefficient Zero Gate Voltage Drain Current Gate to Source Leakage Current Cteristics Gate to Source Threshold Voltage Gate to Source Threshold Voltage Temperature Coefficient Drain to Source On Resistance Forward Transconductance Characteristics Input Capacitance Output Capacitance Reverse Transfer Capacitance Gate Resistance Characteristics Turn-On Delay Time Rise Time Turn-Off Delay Time Fall Time Total Gate Charge at 10V Gate to Source Gate Charge Gate to Drain "Miller" Charge rce Diode Characteristics Source to Drain Diode Forward Voltage Reverse Recovery Time	CoefficientID $250\mu$ A, referenced to $25^{\circ}$ CZero Gate Voltage Drain Current $V_{DS} = 48V, V_{GS} = 0V$ Gate to Source Leakage Current $V_{GS} = \pm 20V, V_{DS} = 0V$ CteristicsGate to Source Threshold Voltage $I_D = 250\mu$ A, referenced to $25^{\circ}$ CGate to Source Threshold Voltage $I_D = 250\mu$ A, referenced to $25^{\circ}$ CTemperature Coefficient $I_D = 250\mu$ A, referenced to $25^{\circ}$ CDrain to Source On Resistance $V_{GS} = 10V, I_D = 10.6A$ Drain to Source On Resistance $V_{GS} = 10V, I_D = 10.6A$ , $T_J = 125^{\circ}$ CForward Transconductance $V_{DS} = 10V, I_D = 10.6A$ CharacteristicsInput CapacitanceInput Capacitance $V_{DS} = 30V, V_{GS} = 0V, f = 10.6A$ Output Capacitance $f = 1MHz$ Characteristicsf = 10.6ATurn-On Delay Time $F = 10.6A$ Rise Time $V_{DD} = 30V, I_D = 10.6A$ Turn-Off Delay Time $V_{GS} = 0V to 10V$ Fall Time $V_{GS} = 0V to 10V$ Gate to Source Gate Charge $I_D = 10.6A$ Gate to Drain "Miller" Charge $V_{GS} = 0V, I_S = 10.6A$ (Note 2)Reverse Recovery Time $I_C = 10.6A$ di/dt = 100A/us	CoefficientID $250\mu$ A, referenced to $25^{\circ}$ CZero Gate Voltage Drain Current $V_{DS} = 48V, V_{GS} = 0V$ Gate to Source Leakage Current $V_{GS} = \pm 20V, V_{DS} = 0V$ CteristicsGate to Source Threshold Voltage $V_{GS} = V_{DS}, I_D = 250\mu$ A2Gate to Source Threshold Voltage $I_D = 250\mu$ A, referenced to $25^{\circ}$ CTemperature Coefficient $V_{GS} = 10V, I_D = 10.6A$ 2Drain to Source On Resistance $V_{GS} = 10V, I_D = 10.6A$ 2Forward Transconductance $V_{DS} = 10V, I_D = 10.6A$ 2CharacteristicsInput Capacitance $V_{DS} = 30V, V_{GS} = 0V, f = 10.6A$ 2CharacteristicsInput Capacitance $f = 1MHz$ 2CharacteristicsInput Capacitance $f = 100K, R_{GEN} = 6\Omega, f = 100K, R_{GEN} = 6\Omega$ 2Turn-On Delay Time $V_{GS} = 0V, I_D = 10.6A$ 22Fail Time $V_{GS} = 0V to 10V, R_{GEN} = 6\Omega$ 22Fail Time $V_{GS} = 0V to 10V, R_{DD} = 30V, I_D = 10.6A$ 2Total Gate Charge at $10V$ $V_{GS} = 0V to 10V, R_{DD} = 30V, I_D = 10.6A$ 2Gate to Source Gate Charge $V_{GS} = 0V to 10V, R_{DD} = 30V, I_D = 10.6A$ 2Fail TimeInput Charge12Ctore Chorde Characteristics $V_{GS} = 0V, I_S = 10.6A, (Note 2)$ 2Reverse Recovery Time $V_{GS} = 0V, I_S = 10.6A, (Note 2)$ 2Reverse Recovery Time $V_{GS} = 0V, I_S = 10.6A, (Note 2)$ 2	CoefficientID250µA, referenced to 25°C59Zero Gate Voltage Drain Current $V_{DS} = 48V, V_{GS} = 0V$ 6Gate to Source Leakage Current $V_{GS} = \pm 20V, V_{DS} = 0V$ 2Cateristics10 $V_{GS} = \pm 20V, V_{DS} = 0V$ 2Gate to Source Threshold Voltage $V_{GS} = \pm 20V, V_{DS} = 0V$ 2Temperature Coefficient $I_D = 250\muA$ , referenced to 25°C-11Drain to Source On Resistance $V_{GS} = 10V, I_D = 10.6A$ 9.4 $V_{GS} = 10V, I_D = 10.6A, I_J = 125°C15.0Forward TransconductanceV_{DS} = 10V, I_D = 10.6A, I_J = 125°C15.0Forward TransconductanceV_{DS} = 10V, I_D = 10.6A, I_J = 10.6A, I_J = 10.6A, I_J = 10.6A26Characteristics1200375Input CapacitanceV_{DS} = 30V, V_{CS} = 0V, I_J = 10.6A, I_$	$\begin{array}{c c c c c c c c c c c c c c c c c c c $

Pulse Test: Pulse Width < 300μs, Duty cycle < 2.0%.</li>
Starting T<sub>J</sub> = 25°C, L = 3mH, I<sub>AS</sub> = 15A, V<sub>DD</sub> = 60V, V<sub>GS</sub> = 10V.
Pulsed Id please refer to Fig 11 SOA graph for more details.
Computed continuous current limited to Max Junction Temperature only, actual continuous current will be limited by thermal & electro-mechanical application board design.

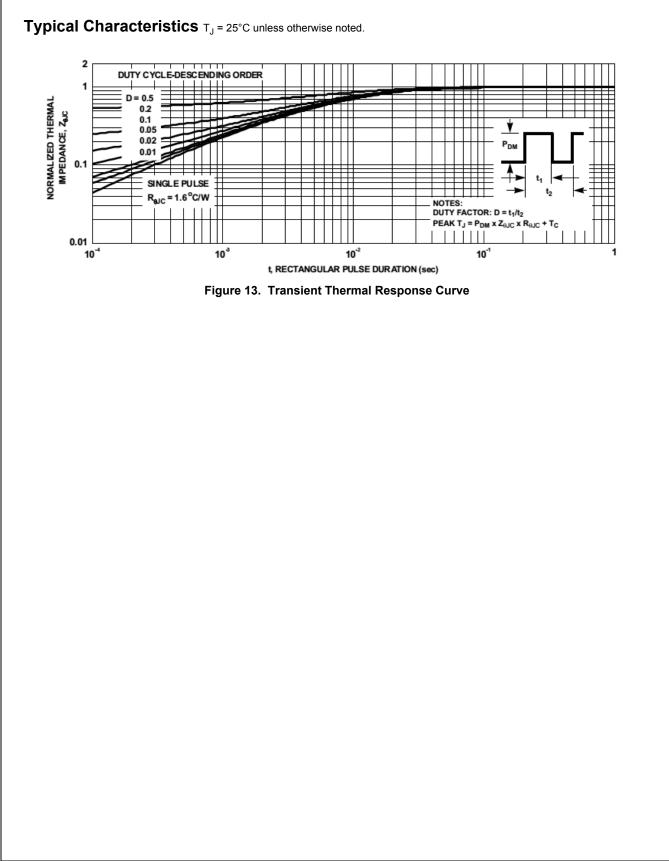


www.fairchildsemi.com



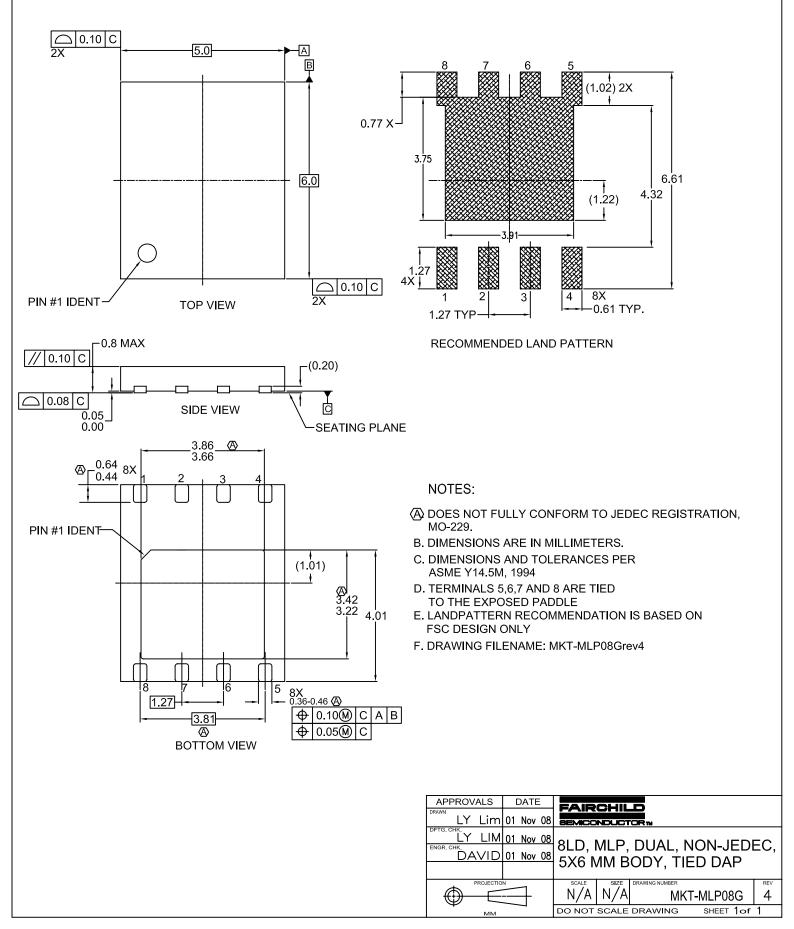


www.fairchildsemi.com



FDMS5672 N-Channel UltraFET Trench<sup>®</sup> MOSFET

	REVISIONS		
NBR	DESCRIPTION	DATE	NAME/SITE
1	RELEASE TO DOCUMENT CONTROL	090305	David/FSPM
2	REVISE TO CORRECT DAP SIZE	080605	David/FSPM
3	I) REVISE TO CORRECT PKG THK		
	II) REVISE THE PKG PROFILE TOLERANCE	210306	CK/FSPM
4	ADD IN LEAD LENGTH FOR LAND PATTERN	220908	LY/FSPM





\* Trademarks of System General Corporation, used under license by Fairchild Semiconductor.

## DISCLAIMER

FAIRCHILD SEMICONDUCTOR RESERVES THE RIGHT TO MAKE CHANGES WITHOUT FURTHER NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY, FUNCTION, OR DESIGN. TO OBTAIN THE LATEST, MOST UP-TO-DATE DATASHEET AND PRODUCT INFORMATION, VISIT OUR WEBSITE AT <u>HTTP://WWW.FAIRCHILDSEMI.COM</u>, FAIRCHILD DOES NOT ASSUME ANY LIABILITY ARISING OUT OF THE APPLICATION OR USE OF ANY PRODUCT OR CIRCUIT DESCRIBED HEREIN; NEITHER DOES IT CONVEY ANY LICENSE UNDER ITS PATENT RIGHTS, NOR THE RIGHTS OF OTHERS. THESE SPECIFICATIONS DO NOT EXPAND THE TERMS OF FAIRCHILD'S WORLDWIDE TERMS AND CONDITIONS, SPECIFICALLY THE WARRANTY THEREIN, WHICH COVERS THESE PRODUCTS.

## AUTHORIZED USE

Unless otherwise specified in this data sheet, this product is a standard commercial product and is not intended for use in applications that require extraordinary levels of quality and reliability. This product may not be used in the following applications, unless specifically approved in writing by a Fairchild officer: (1) automotive or other transportation, (2) military/aerospace, (3) any safety critical application – including life critical medical equipment – where the failure of the Fairchild product reasonably would be expected to result in personal injury, death or property damage. Customer's use of this product is subject to agreement of this Authorized Use policy. In the event of an unauthorized use of Fairchild's product, Fairchild accepts no liability in the event of product failure. In other respects, this product shall be subject to Fairchild's Worldwide Terms and Conditions of Sale, unless a separate agreement has been signed by both Parties.

## ANTI-COUNTERFEITING POLICY

Fairchild Semiconductor Corporation's Anti-Counterfeiting Policy. Fairchild's Anti-Counterfeiting Policy is also stated on our external website, www.fairchildsemi.com, under Terms of Use

Counterfeiting of semiconductor parts is a growing problem in the industry. All manufacturers of semiconductor products are experiencing counterfeiting of their parts. Customers who inadvertently purchase counterfeit parts experience many problems such as loss of brand reputation, substandard performance, failed applications, and increased cost of production and manufacturing delays. Fairchild is taking strong measures to protect ourselves and our customers from the proliferation of counterfeit parts. Fairchild strongly encourages customers to purchase Fairchild parts either directly from Fairchild or from Authorized Fairchild Distributors who are listed by country on our web page cited above. Products customers buy either from Fairchild directly or from Authorized Fairchild Distributors are genuine parts, have full traceability, meet Fairchild's quality standards for handling and storage and provide access to Fairchild's full range of up-to-date technical and product information. Fairchild and our Authorized Distributors will stand behind all warranties and will appropriately address any warranty issues that may arise. Fairchild will not provide any warranty coverage or other assistance for parts bought from Unauthorized Sources. Fairchild is committed to combat this global problem and encourage our customers to do their part in stopping this practice by buying direct or from authorized distributors.

## **PRODUCT STATUS DEFINITIONS**

Definition of Terms				
Datasheet Identification	Product Status	Definition		
Advance Information	Formative / In Design	Datasheet contains the design specifications for product development. Specifications may change in any manner without notice.		
Preliminary	First Production	Datasheet contains preliminary data; supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve design.		
No Identification Needed	Full Production	Datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve the design.		
Obsolete	Not In Production	Datasheet contains specifications on a product that is discontinued by Fairchild Semiconductor. The datasheet is for reference information only.		

Rev. 177